

Search Notes

Application/Control No.

10/528,780

Examiner

HUYEN D. LE

Applicant(s)/Patent under
Reexamination

KURIBAYASHI ET AL.

Art Unit

2615

SEARCHED

Class	Subclass	Date	Examiner
381	398, 423, 424, 426, 432	3/19/2007	HL
181	157		HL
181	163		HL
181	164		HL
181	165		HL
181	167		HL
181	171		HL
181	172		HL
181	173		HL
181	174		HL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR